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COMPOUND FIELD EFFECT POWER TRANSISTOR μ PA1556A

N-CHANNEL POWER MOS FET ARRAY SWITCHING TYPE

DESCRIPTION

The μ PA1556A is N-channel Power MOS FET Array that built in 4 circuits designed for solenoid, motor and lamp driver.

FEATURES

- 4 V driving is possible
- Large Current and Low On-state Resistance

 $ID(pulse) = \pm 20 A$

RDS(on) = 0.20Ω TYP. (Vgs = 10 V)

RDS(on) = 0.25Ω TYP. (Vgs = 4 V)

- Low Capacitance Ciss = 700 pF TYP.
- Gate Protecter built in.
- 2.54 mm Pitch (0.1 inch)

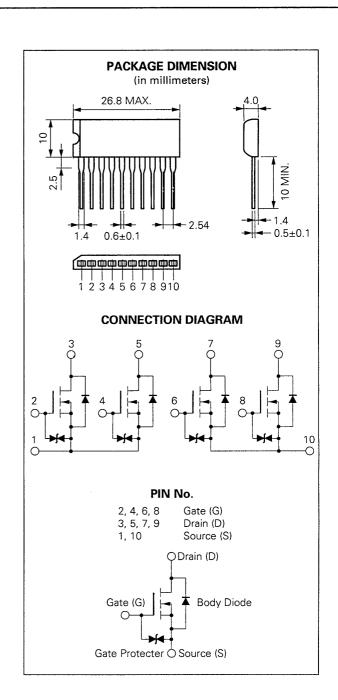
ORDERING INFORMATION

| Part Number | Package | Quality Grade | | |
|--------------------|------------|---------------|--|--|
| μ P A1556AH | 10 Pin SIP | Standard | | |

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C)

| Drain to Source Voltage | Voss | 100 | V | | | |
|--------------------------------------|--------------------|-------------|--------|--|--|--|
| Gate to Source Voltage (AC) | Vgss | ±20 | V | | | |
| Gate to Source Voltage (DC) | Vgss | +20,-10 | V | | | |
| Drain Current (DC) | ID(DC) | ±5.0 | A/unit | | | |
| Drain Current (pulse) | ID(pulse)* | ±20 | A/unit | | | |
| Total Power Dissipation (4 circuits) | | | | | | |
| <tc 25="" =="" °c=""></tc> | P _{T1} | 28 | W | | | |
| Total Power Dissipation (4 circ | cuits) | | | | | |
| <Ta = 25 °C $>$ | P _{T2} | 3.5 | W | | | |
| Storage Temperature | T _{stg} - | -55 to +150 |) °C | | | |
| Junction Temperature | T_j | 150 | °C | | | |
| PW ≦ 10 μs, Duty Cycle ≦ 1 % | | | | | | |



ELECTRICAL CHARACTERISTICS (Ta = 25 °C)

| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT | TEST CONDITIONS | |
|-------------------------------------|----------------------|------|------|------|------|---|--|
| Drain Leakage Current | loss | | | 10 | μΑ | V _{DS} = 100 V, V _{GS} = 0 | |
| Gate to Source Leakage Current | lgss | | | ±10 | μΑ | V _G S = ±20 V, V _D S = 0 | |
| Gate to Source Cutoff Voltage | V _{GS(off)} | 1.0 | | 2.5 | ٧ | Vps = 10 V, lp = 1 mA | |
| Forward Transfer Admittance | yfs | 4.0 | | | S | Vps = 10 V, Ip = 3 A | |
| Drain to Source On-state Resistance | RDS(on)1 | | 0.20 | 0.25 | Ω | Vgs = 10 V, ID = 3 A | |
| Drain to Source On-state Resistance | RDS(on)2 | | 0.25 | 0.33 | Ω | Vgs = 4 V, ID = 3 A | |
| Input Capacitance | Ciss | | 700 | | pF | V _{DS} = 10 V | |
| Output Capacitance | Coss | | 200 | | pF | Vgs = 0 | |
| Reverse Transfer Capacitance | Crss | | 30 | | pF | f = 1.0 MHz | |
| Turn-On Delay Time | td(on) | | 35 | | ns | $I_D = 3 A$ $V_{GS} = 10 V$ $V_{CC} = 50 V$ $R_L = 17 Ω$, $R_{in} = 10 Ω$ See Fig. 1 | |
| Rise Time | tr | | 60 | | ns | | |
| Turn-Off Delay Time | td(off) | | 800 | | ns | | |
| Fall Time | tf | | 200 | | ns | | |
| Total Gate Charge | QG | | 17 | | nC | Vgs = 10 V | |
| Gate to Source Charge | Qgs | | 2.5 | | nC | ID = 5 A VDD = 80 V | |
| Gate to Drain Charge | Qgp | | 4 | | nC | See Fig. 2 | |
| Diode Forward Voltage | VF(S-D) | | 1.0 | | V | IF = 5 A, VGS = 0 | |
| Reverse Recovery Time | trr | | 120 | | ns | Ir = 5 A, Vgs = 0 | |
| Reverse Recovery Charge | Qrr | | 230 | | nC | di/dt = 50 A/μs | |

Fig. 1 Switching Time Test Circuit

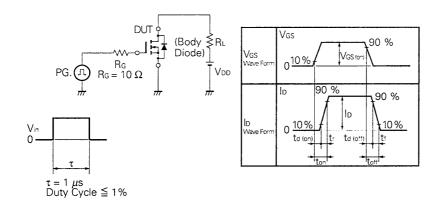
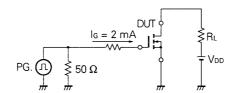
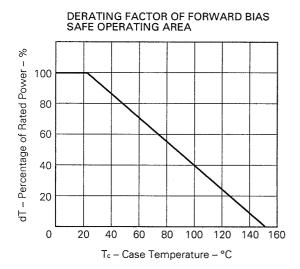
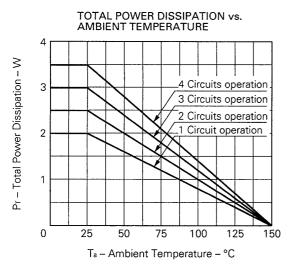


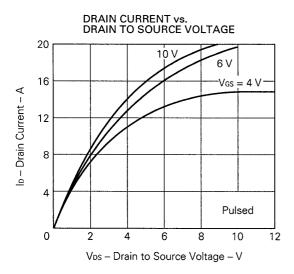
Fig. 2 Gate Charge Test Circuit

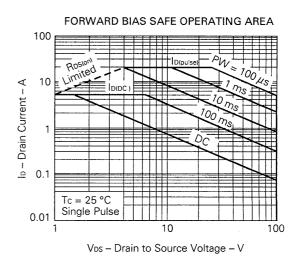


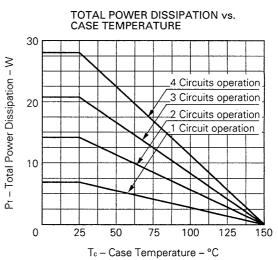
TYPICAL CHARACTERISTICS (Ta = 25 °C)

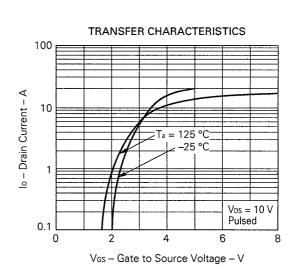


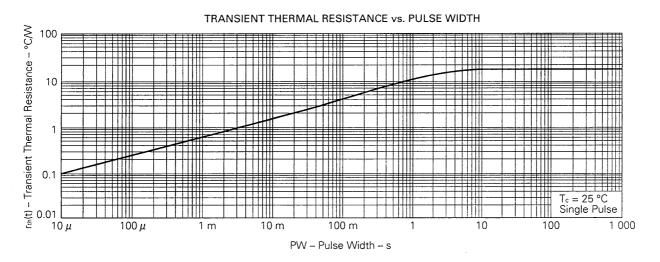


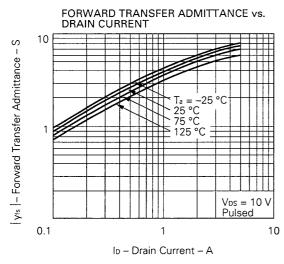


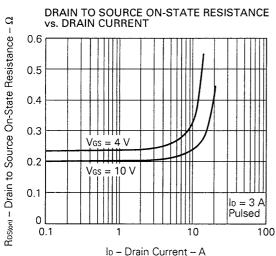


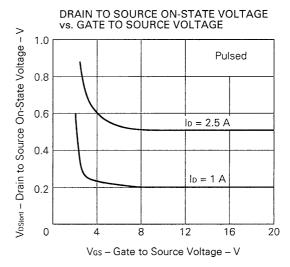


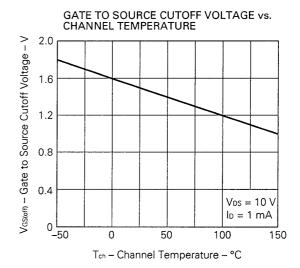


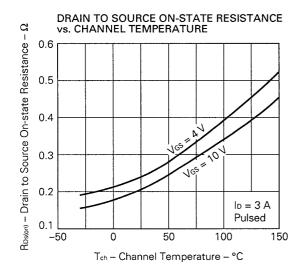


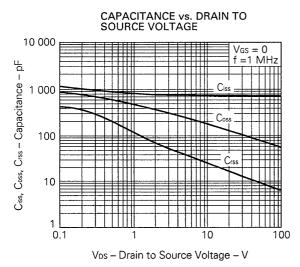


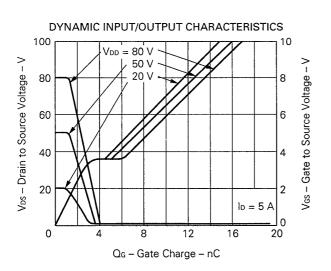


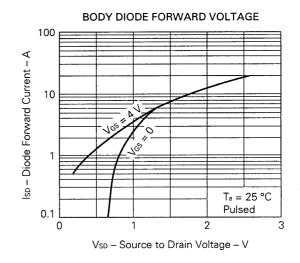


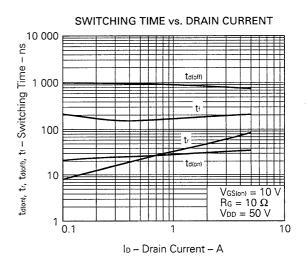


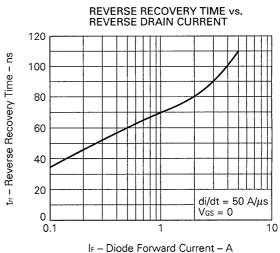














Reference

| Document name | Document No. |
|--|--------------|
| Quality control of NEC semiconductors devices. | TEI-1202 |
| Quality control guide of semiconductors devices. | MEI-1202 |
| Assembly manual of semiconductors devices. | IEI-1207 |
| Safe operating area of Power MOS FET | TEA-1034 |
| Appication circuit using Power MOS FET | TEA-1035 |

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Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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